



Photo Emission Tech., Inc.

760 Calle Plano, Camarillo, CA 93012 USA

Tel: (805) 482-5200 Fax: (805) 482-5252

Email: pet@photoemission.com

EXTERNAL QUANTUM EFFICIENCY MEASUREMENT SYSTEM MODEL # EQE1100

EQE1100 SYSTEM INTRODUCTION

Quantum Efficiency (QE) measurements provide a primary characterization method for completed photovoltaic devices. QE system provides electronics and software designed for fully automated measurement of external quantum efficiency of solar cells. All systems include probes and a fixed plate sample stage for samples up to 150 mm x 150 mm. The main system components include: custom designed software, measurement electronics, and computer system (Windows 8 operating system).



Specifications are subject to change without notice.

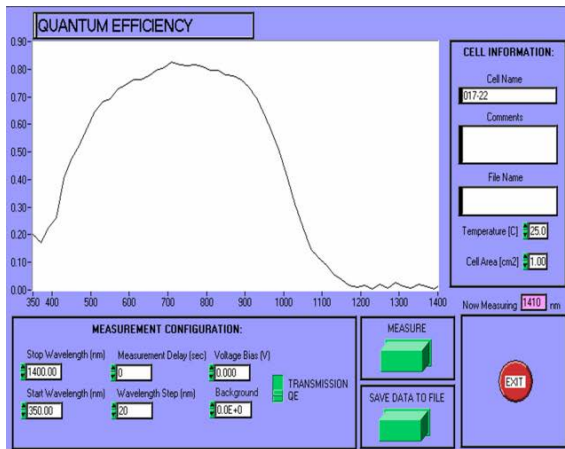


Photo Emission Tech., Inc.
760 Calle Plano, Camarillo, CA 93012 USA
Tel: (805) 482-5200 Fax: (805) 482-5252
Email: pet@photoemission.com

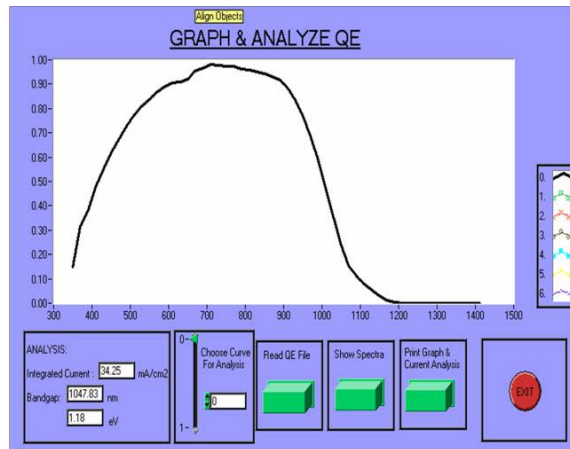
EXTERNAL QUANTUM EFFICIENCY MEASUREMENT SYSTEM MODEL # EQE1100

EQE1100 MAIN SYSTEM CAPABILITIES

The measurement involves focusing monochromatic light to a spot on the device under test, then accurately measuring the photon flux and current from the test cell. The system utilizes a dual beam configuration with lock-in detection, providing an absolute accuracy of $\pm 3\%$. The QE system uses a grating monochromator with silicon/InGaAs/Ge detectors. The system includes automatic order sorting filters and two light sources for monochromatic illumination (a Xenon- arc lamp and a halogen lamp). A single lock-in amplifier is used to measure both the reference detector and test device. The main system comes with all the hardware needed to measure quantum efficiency, a fixed plate sample stage and probes.



The Quantum Efficiency Measurement Screen - example.



Custom-designed Analysis Software-example

Custom designed software using LabView2009™ provides a user-friendly operation for data collection, plotting and analysis. The software provides flexibility and ease of use in the measurement and manipulation of QE. Full manual control over the mono-chromator and order sorting filters is provided for diagnostic purposes. The wavelength range and step size during measurements are user definable. Data stored to disc can be directly examined within the supplied software, or can be exported to a text file readable by most third party software packages. Up to six data sets can be plotted on a single graph for comparison. The calculated QE is convoluted with a standard AM1.5 global spectrum to determine the short circuit current.

Specifications are subject to change without notice



Photo Emission Tech., Inc.

760 Calle Plano, Camarillo, CA 93012 USA

Tel: (805) 482-5200 Fax: (805) 482-5252

Email: pet@photoemission.com

EXTERNAL QUANTUM EFFICIENCY MEASUREMENT SYSTEM MODEL # EQE1100

EQE1100 SYSTEM PERFORMANCE SPECIFICATIONS

ITEM	DESCRIPTION
Solar cell type	Superstrate, Rigid or Flexible, 1-5 mil thickness
Solar cell size	Up to 150 mm x 150 mm
Grid area	At least 2 mm x 2 mm
Cooling	None
Solar cell material	CIGS, CdTe, a-Si based multi-junctions, mono-silicon, organic, etc.
Mono-chromator wavelength accuracy	± 0.6 nm, that mono-chromator can read a wavelength, λ by $\lambda \pm 0.6$ nm.
Mono-chromator max resolution	< 1 nm in visible range, that mono-chromator can read two wavelengths separated by 1 nm.
Measurement range	300 nm to 1,100 nm
Type of measurement	Internal quantum efficiency with options
Operation mode	Automatic, designed software using LabView2009 TM

Specifications are subject to change without notice



Photo Emission Tech., Inc.

760 Calle Plano, Camarillo, CA 93012 USA

Tel: (805) 482-5200 Fax: (805) 482-5252

Email: pet@photoemission.com

EXTERNAL QUANTUM EFFICIENCY MEASUREMENT SYSTEM MODEL # EQE1100

EQE1100 SYSTEM COMPONENTS

ITEM	DESCRIPTION
Computer and software	Custom designed software using LabView2009™ provides a user-friendly operation for data collection, plotting and analysis. The software provides flexibility and ease of use in the measurement and manipulation of QE. Full manual control over the mono-chrometer and order sorting filters is provided for diagnostic purposes. The wavelength range and step size during measurements are user definable. Data stored to disc can be directly examined within the supplied software, or can be exported to a text file readable by most third party software packages. Up to six data sets can be plotted on a single graph for comparison. The calculated QE is convoluted with a standard AM1.5 global spectrum to determine the short circuit current.
Micro-positioners	Sample is mounted on a fixed plate sample stage and probes are provided for making current measurements.
Source Lamps	These systems allow a spot size of about 2 mm x 2 mm with two light sources for monochromatic illumination (a Xenon- arc lamp and a halogen lamp).
Photodiode	It uses two silicon/InGaAs/Ge detectors for the reference detector and test device.
Beam splitter	The measurement involves accurately measuring the photon flux and current from the test cell using a beam splitter
Precision Light Chopper	It provides reference frequency for the lock-in detection
1/8 Mono-chromator	It uses a dual grating mono-chrometer for performing quantum efficiency measurements of cells over the wavelength range from 260nm to 1400nm.
Automated Filter Wheel	The system includes automatic order sorting filters
Digital Lock In Amplifier	The system utilizes a dual beam configuration with lock-in detection.
Frame	Welded steel construction, powder coated
Power requirements	110/220V, 50/60Hz, single-phase, 20 A

Specifications are subject to change without notice



Photo Emission Tech., Inc.

760 Calle Plano, Camarillo, CA 93012 USA

Tel: (805) 482-5200 Fax: (805) 482-5252

Email: pet@photoemission.com

EXTERNAL QUANTUM EFFICIENCY MEASUREMENT SYSTEM MODEL # EQE1100

EQE1100 SYSTEM OPTIONS

INTERNAL QUANTUM EFFICIENCY OPTION

A total reflectance measurement using an integrating sphere is **OPTIONAL** for measurement of Internal Quantum Efficiency (IQE) of a solar cell. The data analysis option calculates $IQE = EQE / (1 - R)$, where R is reflection. For monocrystalline silicon based solar cells, this is a must option.

VOLTAGE BIASING

A DC power supply for voltage biasing the test device at up to ± 5 V can be included. An electric control box on back of the lock-in-amplifier is included to apply a voltage bias. The voltage bias is very useful sometime to separate individual junctions properly from a multi-junction device. It also helps to look at collection losses in a junction.

WHITE LIGHT BIAS AND FILTER LIGHT BIAS CAPABILITY

A white light exposure simulates actual solar light conditions in a solar cell where as filtered light bias at different parts of the solar spectrum helps to isolate contributions from individual cells in a multi-junction cell.

TEMPERATURE CONTROL CAPABILITY

The temperature stage incorporates solid state thermoelectric detectors to provide a controlled measurement of temperature ($\pm 1^\circ\text{C}$) over 10°C to 60°C over a substrate of size up to 150 mm x 150 mm. The system does include a small pump to keep the stage under vacuum so that one does not have moisture build up at low temperatures.

X-Y STAGE CAPABILITY

The X-Y stage allows moving of a sample in both directions up to 120 mm distances. The main platform is supported by four re-circulating ball carrier bearings mounted to precisely aligned linear guide rails, which together are capable of providing smooth motion for loads up to 20 kg. A backlash-free lead-screw produces smooth translation that is directly driven by a two-phase stepper motor capable of 25,600 micro-steps per revolution, thus yielding a positional resolution of less than 100 nm. Magnetic limit switches allow homing and overdriving protection in both forward and reverse directions. It is driven by stepper motor controllers, which come with its own dedicated software package. The stage provides micro-stepping resolution of 40 nm and speeds of up to 12 mm/s.

UNIVERSAL SAMPLE HANDLING CAPABILITY

The stage allows the measurement of a solar cell both in superstrate and substrate structures.

CALIBERATED DETECTORS

PET will provide two NIST traceable third party calibrated detectors for reference. Detectors will include a silicon photodiode, calibrated from 250-1100 nm and interface cables to connect detectors to the QE system.

Specifications are subject to change without notice